



LinBIST for OptimATE

Automated Analog Built-In Self-Test

FEATURES

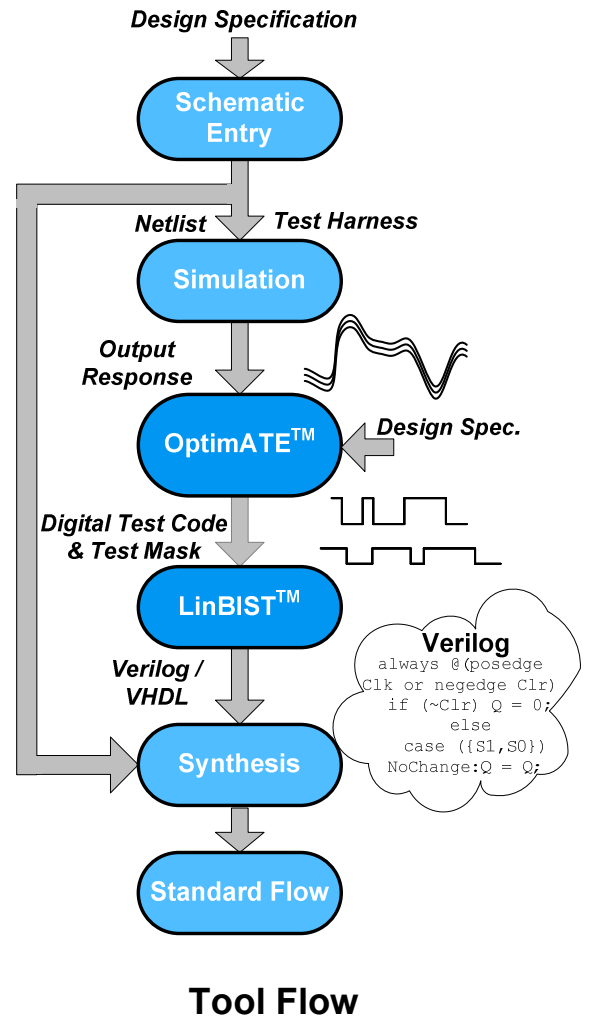
- Automatically generates optimized BIST hardware (Verilog / VHDL) in minutes
- Decimates production test costs
- Eliminates production Analog ATE
- Minimal on-chip test circuitry (primarily digital)
- Improves reliability by in-field monitoring
- Seamless integration with existing design flow
- Serial and Parallel Interface options
- Programmable Fault Handling
- Intuitive GUI driven control
- Fully compliant with OptimATE®

DESCRIPTION

In conjunction with OptimATE®, LinBIST provides a complete automated solution for Built-In Self-Test (BIST) of analog circuits. This innovative technology offers a generic solution for a wide variety of analog circuits. These range from amplifiers, filters (including switched capacitor architectures), to AGCs, voltage references, relay drivers, line drivers, regulators and even demodulators and RF front ends. For ADC and DAC testing see LinBIST datasheet.

APPLICATIONS

- BIST solutions for Analog Mixed-Signal ICs
- Wafer probe, final, field and continuous monitoring test (Automotive, consumer, safety critical etc.)



Overview

